



FOR IMMEDIATE RELEASE

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**AEHR TEST SYSTEMS APPOINTS GREGORY PERKINS  
AS VICE PRESIDENT OF WORLDWIDE SALES AND SERVICE**

**Fremont, CA (June 8, 2004)** -- Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced that Gregory Perkins has been appointed Vice President of Worldwide Sales and Service. He will direct Aehr Test's sales, customer service and applications groups.

Mr. Perkins has over 25 years of capital equipment sales and marketing experience. Prior to joining Aehr Test Systems, Mr. Perkins was Vice President of North American and European Sales for publicly traded Electroglas Corporation, a producer of semiconductor wafer probers. Before that, Mr. Perkins was Vice President of Sales at Advantest America, Inc. and Vice President of Worldwide Sales and Field Operations for LTX Corporation, both semiconductor tester companies. Mr. Perkins also held various management positions at General Electric Company over nearly 20 years.

"We are very pleased to have someone of Greg's caliber join us. He brings strong expertise in back-end semiconductor equipment sales to Aehr Test," said Rhea Posedel, chairman and chief executive officer of Aehr Test Systems. "We are confident that his experience and industry relationships will help strengthen and expand our worldwide customer base."

**About Aehr Test Systems**

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,000 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX<sup>TM</sup>, MTX, MAX3 and MAX4 systems, and the DiePak<sup>®</sup> carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at [www.aehr.com](http://www.aehr.com).

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